Search Notes

Application/Contro	l No.	Applicant(s) Reexaminati	/Patent under on
10/681,544		NG ET AL.	
Examiner		Art Unit	
Ernest F. Karlsen		2829	

SEARCHED					
Class	Subclass	Date	Examiner		
324	751 765	4/20/2005	E.7.K		
714	736 737	4/20/2005	E.T.K		
			•		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
324	751 765	4/20/2005	87.8	

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
voltage adj contrast and electron adj beam library same cell same test same semiconductor	4/20/2005	E.K